



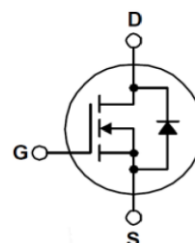
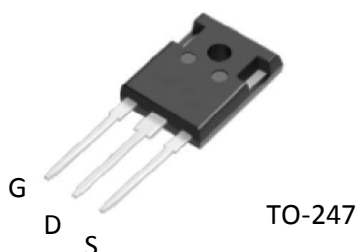
TSK50N50M

500V N-Channel MOSFET

Features

This Power MOSFET is produced using Truesemi's advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

- 50A, 500V, Max. $R_{DS(on)} = 0.11\Omega$ @ $V_{GS} = 10V$
- Low gate charge
- High ruggedness
- 100% avalanche tested
- RoHS compliant device



Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter		Value	Units
V_{DS}	Drain-Source Voltage		500	V
V_{GS}	Gate-Source Voltage		± 30	V
I_D	Drain Current	$T_c = 25^\circ\text{C}$	50	A
		$T_c = 100^\circ\text{C}$	30	A
I_{DM}	Pulsed Drain Current	(Note 1)	184	A
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	2116	mJ
I_{AS}	Single avalanche current	(Note 1)	50	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	29	mJ
P_D	Power Dissipation ($T_c = 25^\circ\text{C}$)		290	W
T_J	Junction temperature		150	$^\circ\text{C}$
T_{stg}	Storage temperature range		-55~150	$^\circ\text{C}$

Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.43	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	50	$^\circ\text{C/W}$

Electrical Characteristics $T_c=25\text{ }^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	2.0	--	4.0	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 25\text{ A}$	--	0.09	0.11	Ω
g_{fs}	Forward transfer conductance	$V_{DS} = 10\text{ V}, I_D = 25\text{ A}$ (Note 4)	--	5.1	--	S

Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	500	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{ V}, V_{GS} = 0\text{ V}$	--	--	10	μA
I_{GSS}	Gate leakage current	$V_{DS}=0\text{ V}, V_{GS}=\pm 20\text{ V}$	--	--	± 100	nA

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	8349	--	pF
C_{oss}	Output Capacitance		--	658	--	pF
C_{rss}	Reverse Transfer Capacitance		--	67	--	pF

Switching Characteristics

$t_{d(on)}$	Turn-On Time	$V_{DD} = 250\text{ V}, I_D = 23\text{ A},$ $R_G = 25\text{ }\Omega$ (Note 4)	--	62	--	ns
t_r	Turn-On Rise Time		--	24	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	188	--	ns
t_f	Turn-Off Fall Time		--	23	--	ns
Q_g	Total Gate Charge	$V_{DS}=400\text{ V}, I_D = 25\text{ A},$ $V_{GS} = 10\text{ V}$ (Note 4)	--	180	--	nC
Q_{gs}	Gate-Source Charge		--	39	--	nC
Q_{gd}	Gate-Drain Charge		--	57	--	nC

Source-Drain Diode Maximum Ratings and Characteristics

I _S	Continuous Source-Drain Diode Forward Current		--	--	46	A
I _{SM}	Pulsed Source-Drain Diode Forward Current		--	--	184	
V _{SD}	Source-Drain Diode Forward Voltage	I _S = 50A, V _{GS} = 0 V	--	--	1.5	V
t _{rr}	Reverse Recovery Time	I _S = 50A, V _{GS} = 0 V di _F /dt = 100 A/μs (Note 4)	--	487	--	ns
Q _{rr}	Reverse Recovery Charge		--	6.9	--	uC

NOTES:

1. Repeated rating: Pulse width limited by safe operating area
2. $L=2\text{ mH}$, $I_{AS}=50\text{ A}$, $V_{DD}=50\text{ V}$, $R_G=25\text{ }\Omega$, Starting $T_J=25\text{ }^{\circ}\text{C}$
3. Pulse test: Pulse width $\leq 300\text{ }\mu\text{s}$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature typical characteristics

Typical Characteristics

Fig. 1 $I_D - V_{DS}$

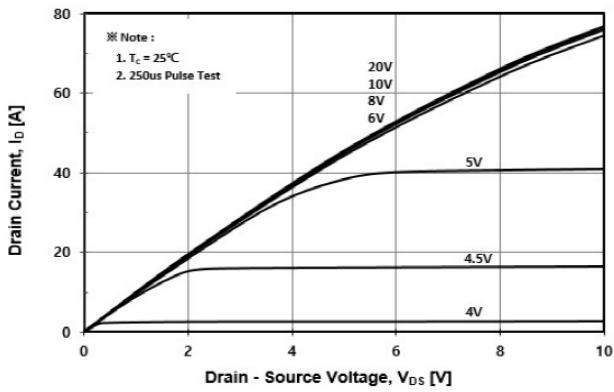


Fig. 2 $I_D - V_{GS}$

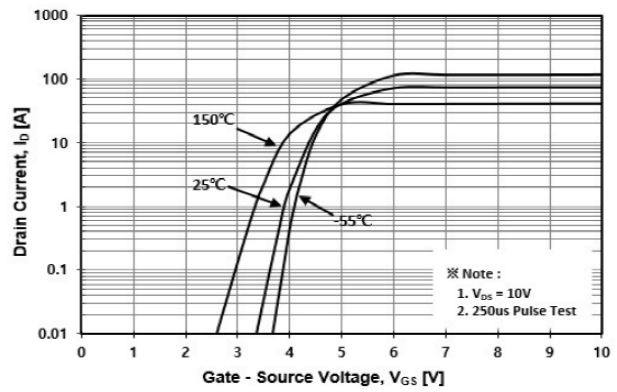


Fig. 3 $R_{DS(ON)} - I_D$

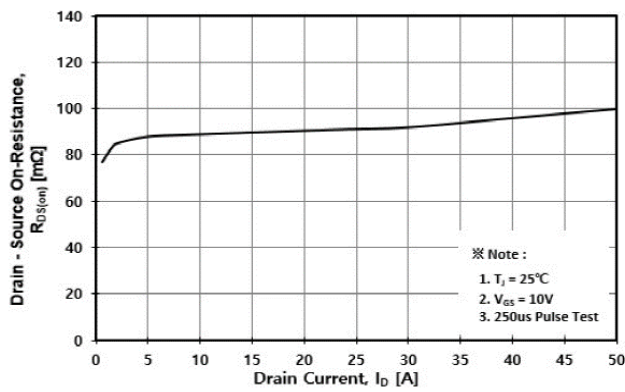


Fig. 4 $I_S - V_{SD}$

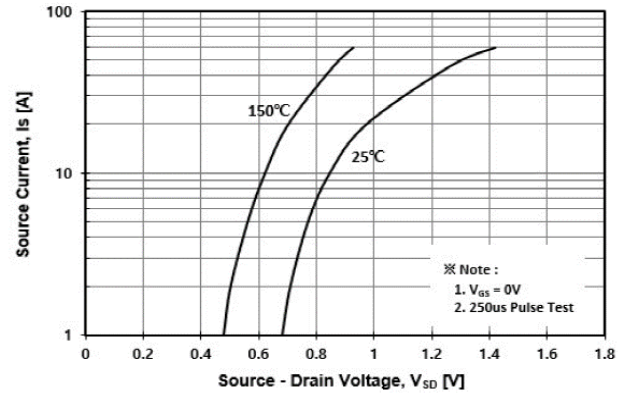


Fig. 5 Capacitance - V_{DS}

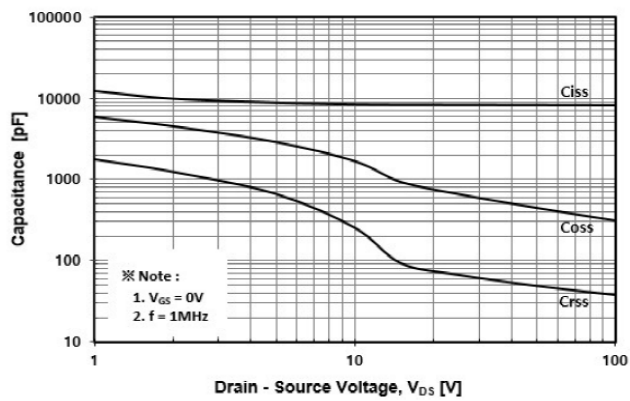
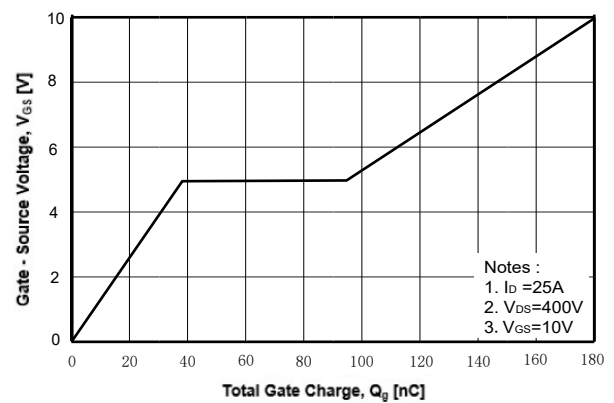


Fig. 6 $V_{GS} - Q_g$



Typical Characteristics Curve (Continue)

Fig. 7 $BV_{DSS} - T_J$

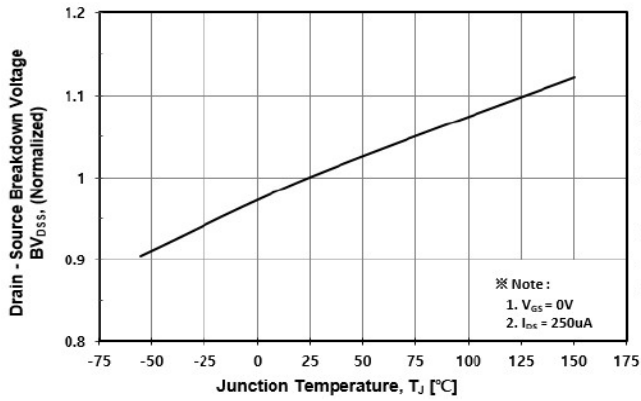


Fig. 8 $R_{DS(ON)} - T_J$

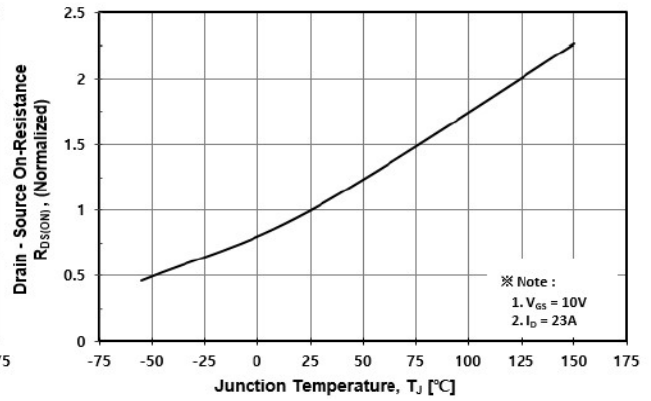


Fig. 9 $I_D - T_C$

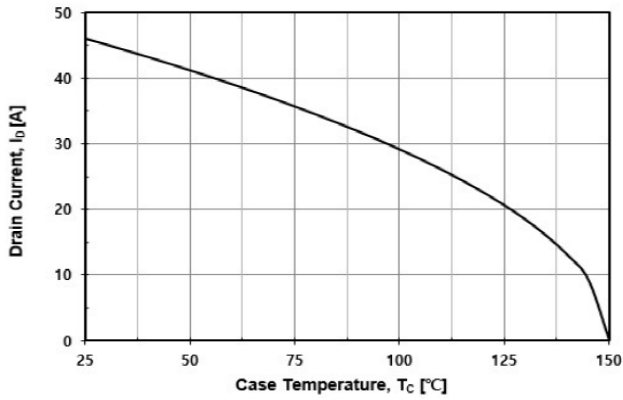


Fig. 10 Safe Operating Area

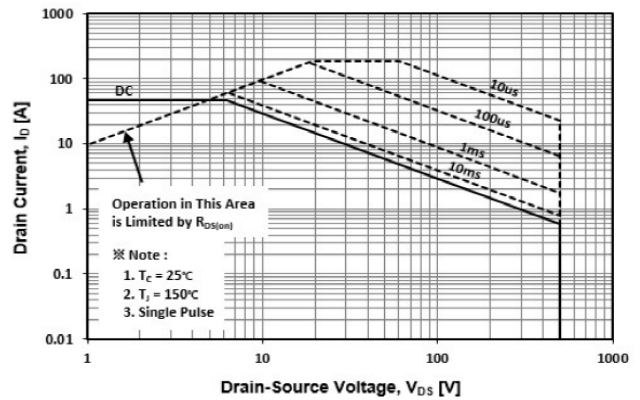


Fig. 11 Transient Thermal Impedance

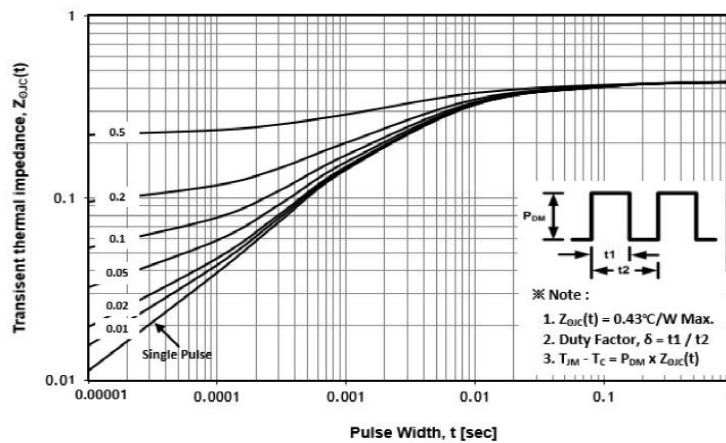


Fig. 12 Gate Charge Test Circuit & Waveform

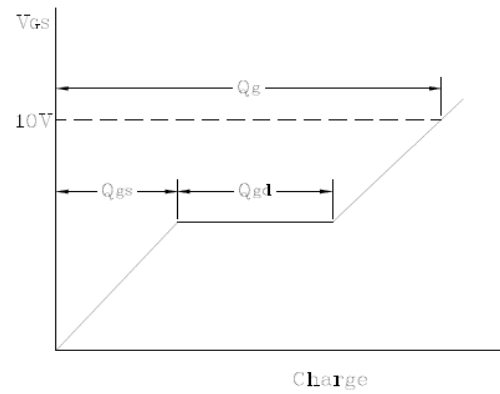
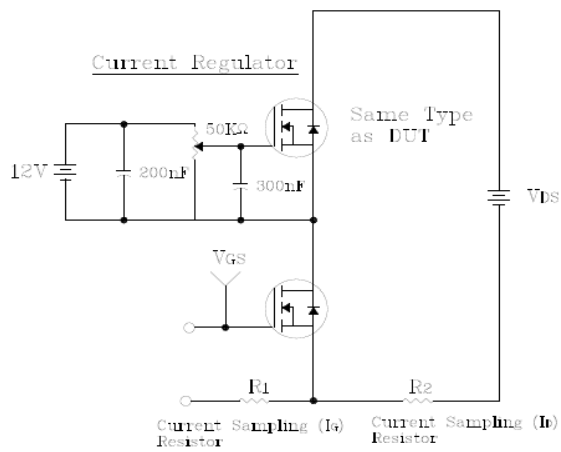


Fig. 13 Resistive Switching Test Circuit & Waveform

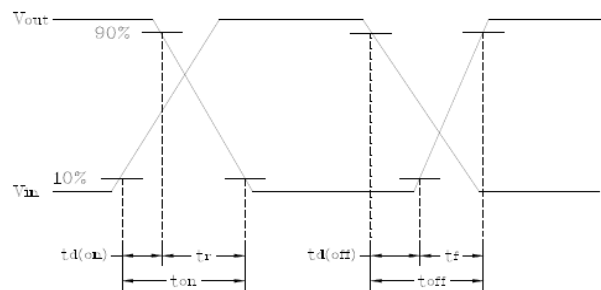
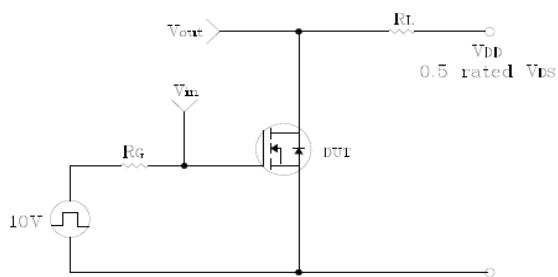
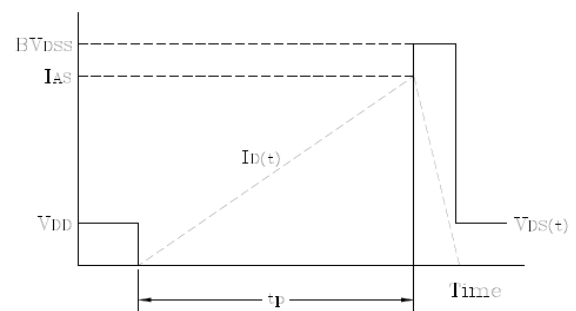
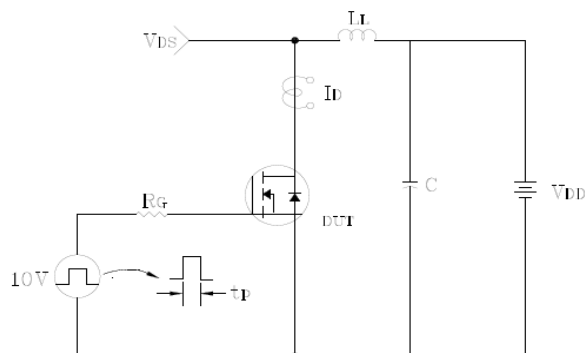
Fig. 14 E_{AS} Test Circuit & Waveform

Fig. 15 Diode Reverse Recovery Time Test Circuit & Waveform

